

**ABSTRACT**

[54] One embodiment of a method comprises retrieving test data corresponding to test results from a plurality of fuses, each one of the plurality of fuses residing on a different one of a plurality of semiconductor devices and each one of the plurality of fuses having a common location on the semiconductor devices, determining from the test data which of the plurality of fuses are defective fuses, and specifying on an output report the common location of the determined defective fuses when a number of the defective fuses are at least equal to a predefined portion of the plurality of fuses.